

Notice of References Cited	Application/Control No. 10/815,640		Applicant(s)/Patent Under Reexamination LAPSTUN ET AL.	
	Examiner Madeleine AV Nguyen		Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0041505	02-2006	Enyart, Robert A.	705/040
*	B	US-6,999,938	02-2006	Libman, Richard M.	705/10
*	C	US-6,421,678	07-2002	Smiga et al.	707/102
*	D	US-6,366,913	04-2002	Fitler et al.	707/9
*	E	US-6,351,764	02-2002	Voticky et al.	709/207
*	F	US-2006/0004642	01-2006	Libman, Richard Marc	705/026
*	G	US-2004/0010419	01-2004	Sinnott, Timothy John	705/2
*	H	US-6,614,931	09-2003	Nalder, Gregory T.	382/187
*	I	US-6,493,103	12-2002	Toyoda et al.	358/1.15
*	J	US-6,466,330	10-2002	Mori, Yukikazu	358/1.15
*	K	US-6,154,290	11-2000	Makita, Hiroshi	358/440
*	L	US-6,108,103	08-2000	Kurozasa, Yoshiharu	358/405
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.